



Description

The FQD13N06L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 20A$

$R_{DS(ON)} < 32m\Omega$ @ $V_{GS}=10V$

Application

Battery protection

Load switch

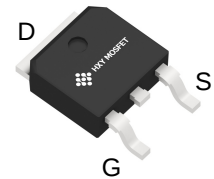
Uninterruptible power supply

Ordering Information

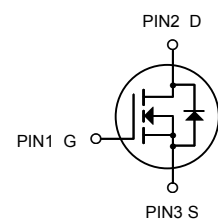
Product ID	Pack	Brand	Qty(PCS)
FQD13N06L	TO-252-2L(TO-252AA)	HXY MOSFET	2500

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	20	A
$I_D@T_C=100^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	10	A
I_{DM}	Pulsed Drain Current ²	80	A
EAS	Single Pulse Avalanche Energy ³	38	mJ
$P_D@T_C=25^{\circ}C$	Total Power Dissipation ⁴	34.7	W
T_{STG}	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$



TO-252-2L
(TO-252AA)



N-Channel MOSFET



Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60	-	-	V
Gate-Body Leakage Current		I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	$T_J=25^{\circ}C$	I_{DSS}	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1	μA
	$T_J=100^{\circ}C$			-	-	100	
Gate-Threshold Voltage		$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.7	2.5	V
Drain-Source on-Resistance ⁴		$R_{DS(on)}$	$V_{GS} = 10V, I_D = 10A$	-	25	32	m Ω
			$V_{GS} = 4.5V, I_D = 5A$	-	31.5	40	
Forward Transconductance ⁴		g_{fs}	$V_{DS} = 5V, I_D = 10A$	-	15.5	-	S
Dynamic Characteristics ⁵							
Input Capacitance		C_{iss}	$V_{DS} = 30V, V_{GS} = 0V, f = 1MHz$	-	1355	-	pF
Output Capacitance		C_{oss}		-	60	-	
Reverse Transfer Capacitance		C_{rss}		-	49	-	
Gate Resistance		R_G	$f = 1MHz$	-	1.2	-	Ω
Switching Characteristics ⁵							
Total Gate Charge		Q_g	$V_{GS} = 10V, V_{DD} = 30V, I_D = 10A$	-	22	-	nC
Gate-Source Charge		Q_{gs}		-	4.2	-	
Gate-Drain Charge		Q_{gd}		-	6.9	-	
Turn-on Delay Time		$t_{d(on)}$	$V_{GS} = 10V, V_{DD} = 30V, R_G = 3\Omega, I_D = 10A$	-	6.4	-	ns
Rise Time		t_r		-	15.3	-	
Turn-off Delay Time		$t_{d(off)}$		-	25	-	
Fall Time		t_f		-	7.6	-	
Body Diode Reverse Recovery Time		t_{rr}	$I_F = 10A, dI_F/dt = 100A/\mu s$	-	26	-	ns
Body Diode Reverse Recovery Charge		Q_{rr}		-	45	-	nC
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V_{SD}	$I_S = 10A, V_{GS} = 0V$	-	-	1.2	V
Continuous Source Current	$T_C = 25^{\circ}C$	I_S	-	-	-	20	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^\circ\text{C}$
2. The EAS data shows Max. rating . The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.4mH, I_{AS}=14A$
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.



Typical Characteristics

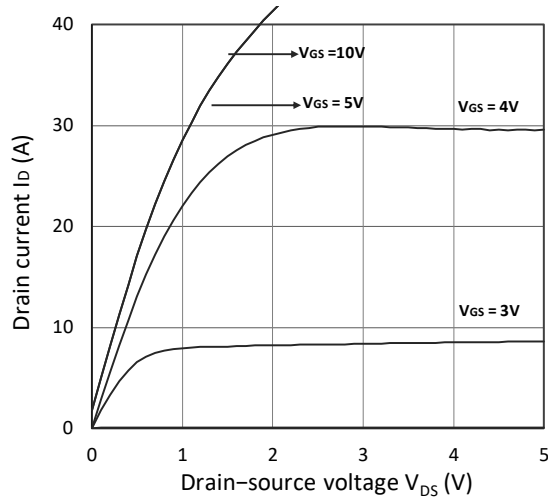


Figure 1. Output Characteristics

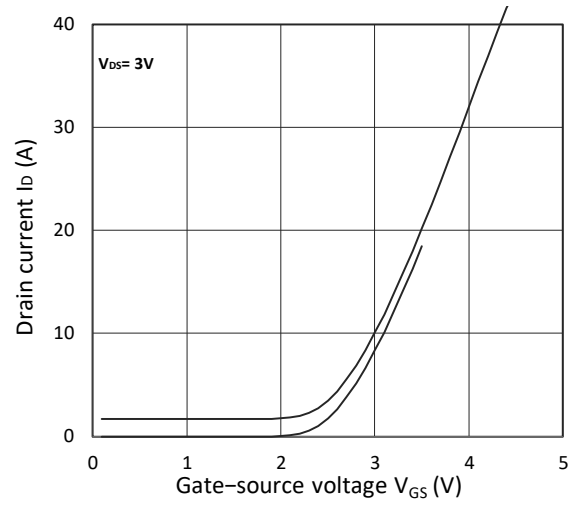


Figure 2. Transfer Characteristics

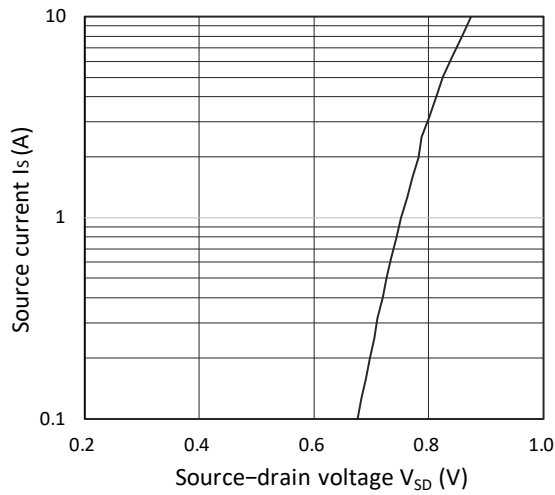


Figure 3. Forward Characteristics of Reverse

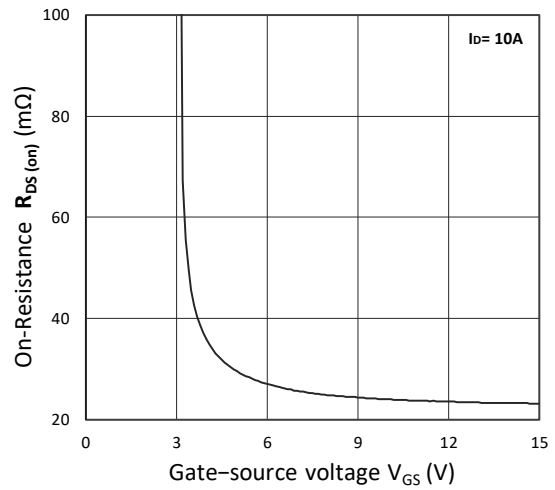


Figure 4. $R_{DS(on)}$ vs. V_{GS}

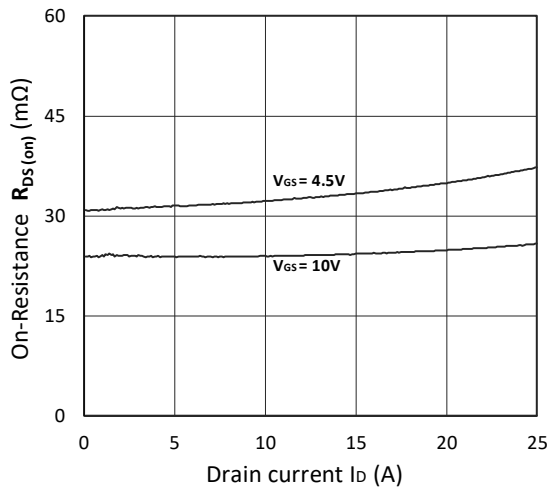


Figure 5. $R_{DS(on)}$ vs. I_D

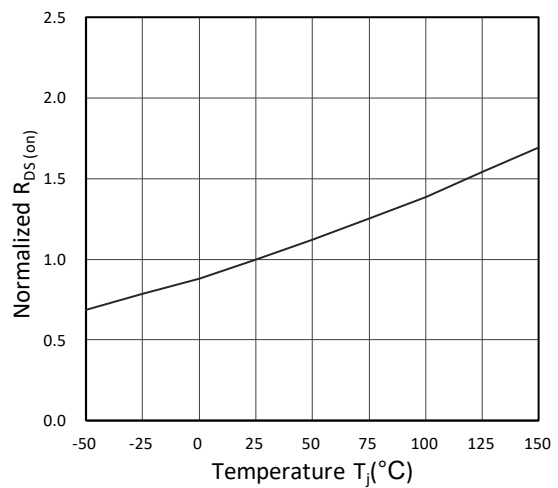


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature



Figure 7. Capacitance Characteristics

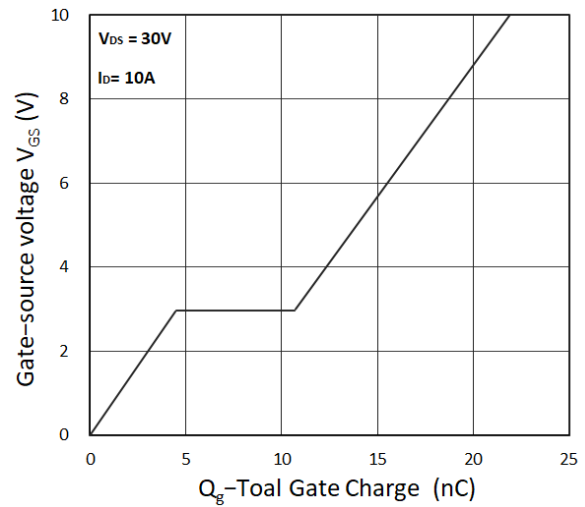


Figure 8. Gate Charge Characteristics



Figure 9. Power Dissipation

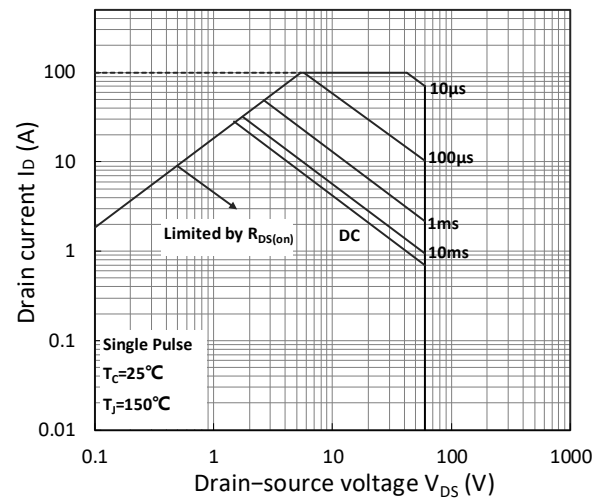


Figure 10. Safe Operating Area



Figure 11. Normalized Maximum Transient Thermal Impedance



N-Channel Enhancement Mode MOSFET

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	



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